

tg	-40-150		
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(T<sub>j</sub>=25 unless otherwise specified)

Symbol	Test Condition	Quadrant	Value		Unit
I <sub>GT</sub>	V <sub>D</sub> =12V R <sub>L</sub> =33	- -	MAX.	5	mA
				10	
V <sub>GT</sub>		ALL	MAX.	1	V
V <sub>GD</sub>	V <sub>D</sub> =V <sub>DRM</sub> T <sub>j</sub> =125 R <sub>L</sub> =3.3k	ALL	MIN.	0.2	V
I <sub>L</sub>	I <sub>G</sub> =1.2I <sub>GT</sub>	- -	MAX.	15	mA
				20	
I <sub>H</sub>	I <sub>T</sub> =500mA		MAX.	10	mA
dV/dt	V <sub>D</sub> =540V Gate Open T <sub>j</sub> =125		MIN.	40	V/μs
(dV/dt) <sub>c</sub>	(dI/dt) <sub>c</sub> =5A/ms, T <sub>j</sub> =110		MIN.	2	V/μs
t <sub>on</sub>	I <sub>G</sub> =20mA I <sub>A</sub> =200mA I <sub>R</sub> =20mA T <sub>j</sub> =25		TYP.	3	

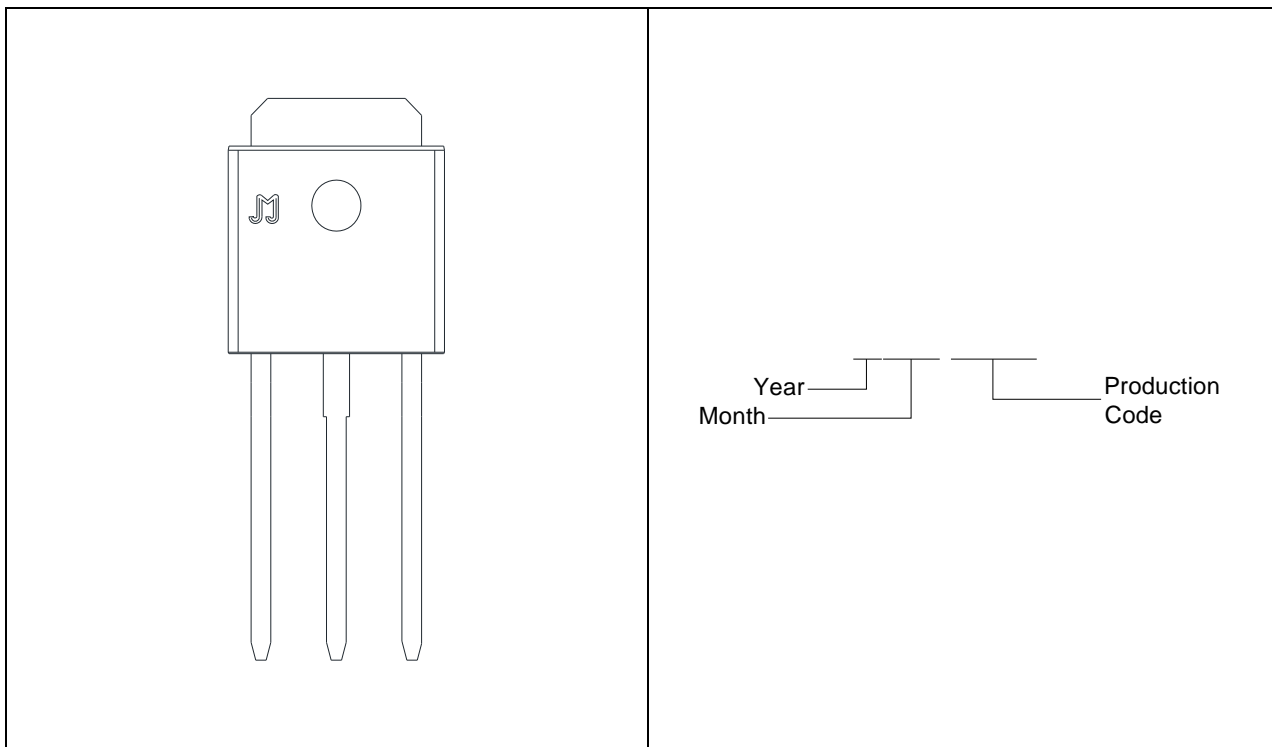
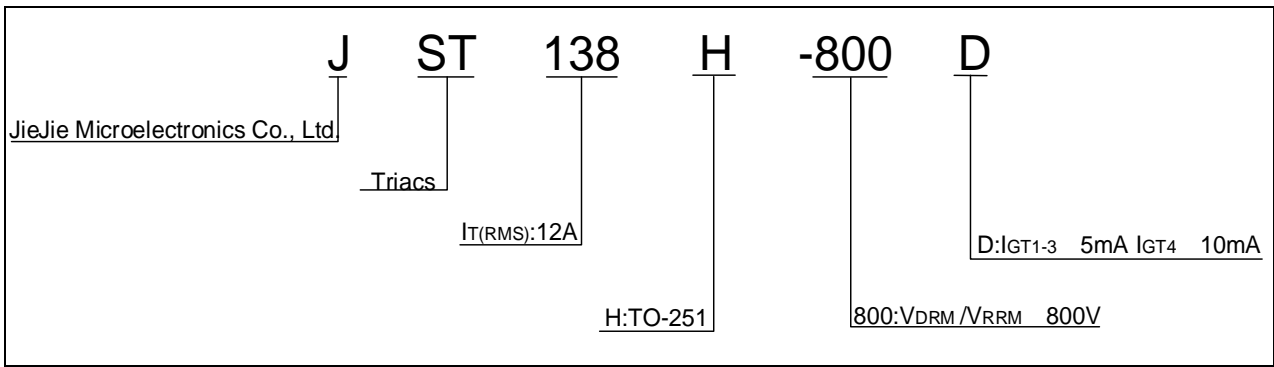
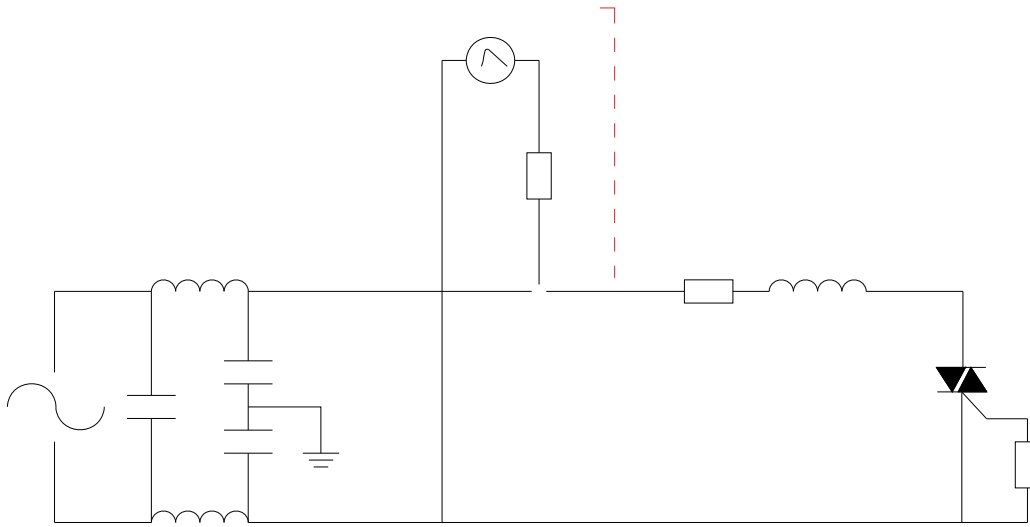


FIG.1:

FIG.7 Test circuit for inductive and resistive loads to IEC-61000-4-5 standards







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